

CoolSiC™ M1 CoolSiC™ MOSFET 650 V G1

The 650 V CoolSiC[™] is built over the solid silicon carbide technology developed in Infineon in more than 20 years. Leveraging the wide bandgap SiC material characteristics, the 650V CoolSiC[™] MOSFET offers a unique combination of performance, reliability and ease of use. Suitable for high temperature and harsh operations, it enables the simplified and cost effective deployment of the highest system efficiency.

Tab Tab

Gate

Pin 1

Driver

Source

Pin 2

Drain

Tab

Source

PG-T0263-7

Features

- Optimized switching behavior at higher currents
- Commutation robust fast body diode with low Q_{fr}
- Superior gate oxide reliability
- T_{i.max}=175°C and excellent thermal behavior
- Lower R_{DS(on)} and pulse current dependency on temperature
- Increased avalanche capability
- Compatible with standard drivers
- Kelvin source provides up to 4 times lower switching losses

Benefits

- · Unique combination of high performance, high reliability and ease of use
- · Ease of use and integration
- Suitable for topologies with continuous hard commutation
- Higher robustness and system reliability
- Efficiency improvement
- · Reduced system size leading to higher power density

Potential applications

- Telecom and Server SMPS
- UPS (uninterruptable power supplies)
- Solar PV inverters
- EV charging infrastructure
- Energy storage and battery formation
- Class D amplifiers

Product validation

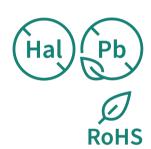
Fully qualified according to JEDEC for Industrial Applications

Please note: The source and sense source pins are not exchangeable. Their exchange might lead to malfunction.



Parameter	Value	Unit	
$V_{DS} @ T_J = 25 ^{\circ}\text{C}$	650	V	
$R_{DS(on),typ}$	260	mΩ	
R _{DS(on),max}	346	mΩ	
$Q_{G,typ}$	6	nC	
I _{DM,max}	19	А	
Q _{oss} @ 400 V	22	nC	
<i>E_{oss}</i> @ 400 V	3.4	μЈ	

Type/Ordering Code	Package	Marking	Related Links
IMBG65R260M1H	PG-TO263-7	65R260M1	see Appendix A



Public

CoolSiC™ MOSFET 650 V G1 IMBG65R260M1H



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1 Maximum ratings

at $T_i = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Davamatav	Cumphal	Values			Linit	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition	
Continuous DC drain current ¹⁾	I _{DDC}	-	-	6 5	А	$T_c = 25 ^{\circ}\text{C}$ $T_c = 100 ^{\circ}\text{C}$	
Peak drain current ²⁾	I _{DM}	-	-	19	А	$T_{\rm c}$ = 25 °C, $V_{\rm GS}$ = 18 V	
Avalanche energy, single pulse	E _{AS}	-	-	30	mJ	I _D = 1.1 A, V _{DD} = 50 V; see table 11	
Avalanche energy, repetitive	E _{AR}	-	-	0.15	mJ	$I_{\rm D}$ = 1.1 A, $V_{\rm DD}$ = 50 V; see table 11	
Avalanche current, single pulse	I _{AS}	-	-	1.1	Α	-	
MOSFET dv/dt ruggedness	dv/dt	-	-	200	V/ns	V _{DS} = 0400 V	
Gate source voltage (static) 3)	V_{GS}	-5	-	23	V	-	
Gate source voltage (transient)	V_{GS}	-7	-	25	V	$t_{pulse} \le 1\%$ duty cycle/ f_{sw}	
Power dissipation	P _{tot}	-	-	65	W	T _c = 25 °C	
Storage temperature	$T_{\rm stg}$	-55	-	150	°C	-	
Operating junction temperature	T _j	-55	-	175	°C	-	
Mounting torque	-	-	-	n.a.	Ncm	-	
Continuous reverse drain current ¹⁾	I _{SDC}	-	-	6	А	$V_{GS} = 18 \text{ V}, T_c = 25 \text{ °C}$ $V_{GS} = 0 \text{ V}, T_c = 25 \text{ °C}$	
Peak reverse drain current ²⁾	I _{SM}	-	-	19	А	$T_{\rm c}$ = 25 °C, $t_{\rm p}$ ≤ 250 ns	
Insulation withstand voltage	$V_{\rm ISO}$			n.a.	V	$V_{\rm rms}$, $T_{\rm c}$ = 25 °C, t = 1 min	

¹⁾ Limited by $T_{j,max}$.

²⁾ Pulse width t_{pulse} limited by $T_{\text{j,max}}$.

³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol		Values			Note / Took Constitution
		Min.	Тур.	Max.	Unit	Note/ Test Condition
Thermal resistance, junction - case	$R_{th(j-c)}$	-	-	2.30	°C/W	-
Thermal resistance, junction - ambient	$R_{th(j-a)}$	-	-	62	°C/W	device on PCB, minimal footprint
Thermal resistance, junction - ambient, SMD version	$R_{th(j-a)}$	-	35	45	°C/W	Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer 70µm thickness) copper area for drain connection and cooling. PCB is vertical without air stream cooling.
Soldering temperature, wave- & reflow soldering allowed	T_{sold}	-	-	260	°C	reflow MSL1



3 Operating range

Table 4 Operating range

Parameter	Symbol	Values			Unit	Note / Tost Candition	
raiailletei	Symbol	Min.	Тур.	Мах.	Ollic	Note/ Test Condition	
Gate-source voltage operating range including undershoots ⁴⁾	V_{GS}	-2	-	20	V	-	
Recommended turn-on voltage	$V_{GS(on)}$	-	18	-	V	-	
Recommended turn-off voltage	$V_{GS(off)}$	-	0	-	V	-	

4)

Important notice: If the gate source voltage of the device in application exceeds the operating range (Table 4), the device $R_{DS,on}$ and $V_{GS(th)}$ might exceed the maximum value stated in the datasheet at the end of the lifetime of the device. In order to ensure sound operation of the device over the planned lifetime, the maximum ratings (Table 2) and the CoolSiCTM MOSFET 650V M1 trench power device application note AN_1907_PL52_1911_144109 must be considered.



4 Electrical characteristics

at T_j = 25 °C, unless otherwise specified

Table 5 Static characteristics

Parameter	Symbol	Values			Unit	Note/ Test Condition
Parameter	Syllibol	Min.	Тур.	Мах.	Ollic	Note/ Test Condition
Drain-source voltage	$V_{\scriptscriptstyle m DSS}$	650	-	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm D} = 0.17 \text{ mA}$
Gate threshold voltage ⁵⁾	$V_{\rm GS(th)}$	3.5	4.5	5.7	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 1.1 \rm mA$
Zero gate voltage drain current	I _{DSS}	-	1 3	100 -	μΑ	$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25 \text{ °C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175 \text{ °C}$
Gate-source leakage current	I_{GSS}	-	-	100	nA	$V_{\rm GS} = 20 \text{ V}, \ V_{\rm DS} = 0 \text{ V}$
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	260 364	346 -	mΩ	$V_{GS} = 18 \text{ V}, I_D = 3.6 \text{ A}, T_j = 25 \text{ °C}$ $V_{GS} = 18 \text{ V}, I_D = 3.6 \text{ A}, T_j = 175 \text{ °C}$
Internal gate resistance	$R_{G,int}$	-	24.0	-	Ω	f= 1 MHz

⁵⁾ Tested after 1 ms pulse at V_{GS} = +20 V.

Table 6 Dynamic characteristics

Parameter	Symbol		Values			Nata/Task Condition
	Symbol	Min.	Тур.	Max.	Unit	Note/ Test Condition
Input capacitance	C _{iss}	-	201	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Reverse transfer capacitance	C _{rss}	-	3.7	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output capacitance ⁶⁾	$C_{\rm oss}$	-	37	48	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output charge ⁶⁾	$Q_{\rm oss}$	-	22	29	nC	calculation based on C _{oss}
Effective output capacitance, energy related ⁷⁾	$C_{ m o(er)}$	-	42	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$
Effective output capacitance, time related ⁸⁾	$C_{\rm o(tr)}$	-	55	-	pF	$I_{\rm D}$ = constant, $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 0400 V
Turn-on delay time	$t_{ m d(on)}$	-	5.3	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 3.6 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Rise time	t _r	-	5.3	-	ns	$V_{\rm DD}$ = 400 V, $V_{\rm GS}$ = 0/18 V, $I_{\rm D}$ = 3.6 A, $R_{\rm G,ext}$ = 1.8 Ω ; see table 10
Turn-off delay time	$t_{ m d(off)}$	-	7.7	-	ns	$V_{\rm DD}$ = 400 V, $V_{\rm GS}$ = 0/18 V, $I_{\rm D}$ = 3.6 A, $R_{\rm G,ext}$ = 1.8 Ω ; see table 10
Fall time	t _f	-	13.0	-	ns	$V_{\rm DD} = 400 \text{V}, \ V_{\rm GS} = 0/18 \text{V},$ $I_{\rm D} = 3.6 \text{A}, \ R_{\rm G,ext} = 1.8 \Omega;$ see table 10



- 6) Maximum specification is defined by calculated six sigma upper confidence bound.
- ⁷⁾ $C_{\rm o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{\rm oss}$ while $V_{\rm DS}$ is rising from 0 to 400 V.
- 8) $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V.

Table 7 Gate charge characteristics

Parameter	Symbol	Values			Unit	Nieto/Test Condition
raiametei	Syllibot	Min.	Тур.	Мах.	Ollic	Note/ Test Condition
Plateau gate to source charge	$Q_{GS(pl)}$	-	1	-	nC	$V_{\rm DD} = 400 \text{V}, I_{\rm D} = 3.6 \text{A},$ $V_{\rm GS} = 0 \text{to} 18 \text{V}$
Gate to drain charge	Q_{GD}	-	1	-	nC	$V_{\rm DD} = 400 \text{V}, I_{\rm D} = 3.6 \text{A},$ $V_{\rm GS} = 0 \text{to} 18 \text{V}$
Total gate charge	Q_{G}	-	6	-	nC	$V_{\rm DD} = 400 \text{V}, I_{\rm D} = 3.6 \text{A},$ $V_{\rm GS} = 0 \text{to} 18 \text{V}$

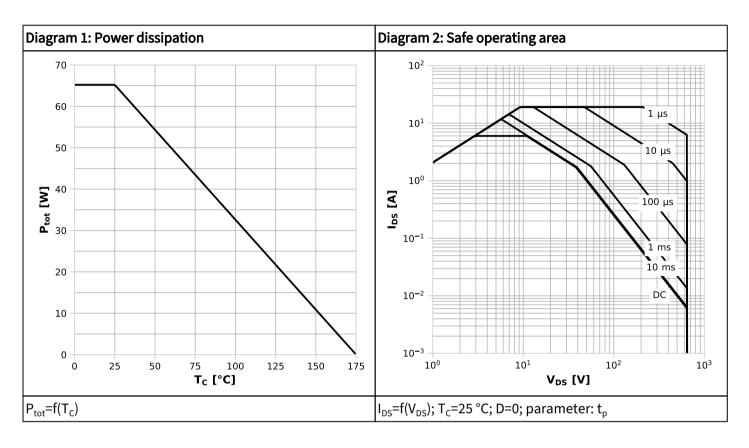
Table 8 Reverse diode characteristics

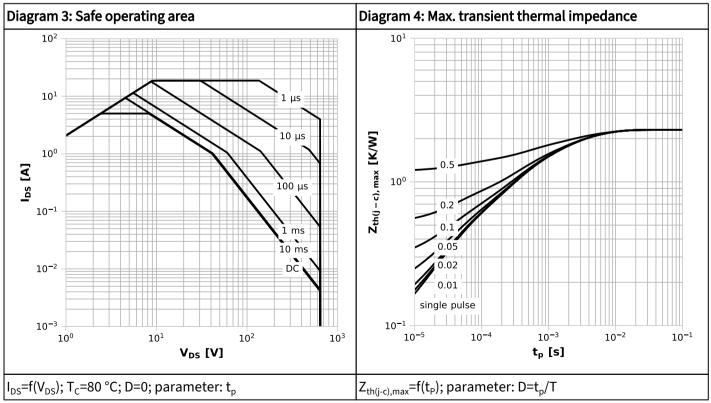
Parameter	Symbol	Values			Unit	Note/ Test Condition	
raianietei	Symbol	Min.	Тур.	Max.	Offic	Note, rest condition	
Drain-source reverse voltage	$V_{\rm SD}$	-	4.0	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm S} = 3.6 \text{ A}, T_{\rm j} = 25 ^{\circ}\text{C}$	
MOSFET forward recovery time	t _{fr}	-	16.6	-	ınc	$V_{DD} = 400 \text{ V}, I_{S} = 3.6 \text{ A},$ $di_{S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$	
MOSFET forward recovery charge ⁹⁾	Q_{fr}	-	33	-	ını	$V_{DD} = 400 \text{ V}, I_{S} = 3.6 \text{ A},$ d i_{S} /d $t = 1000 \text{ A/µs}$; see table 9	
MOSFET peak forward recovery current	I _{frm}	-	4.2	-	А	$V_{DD} = 400 \text{ V}, I_{S} = 3.6 \text{ A},$ d i_{S} /d $t = 1000 \text{ A/}\mu\text{s}$; see table 9	

⁹⁾ Q_{fr} includes Q_{oss} .

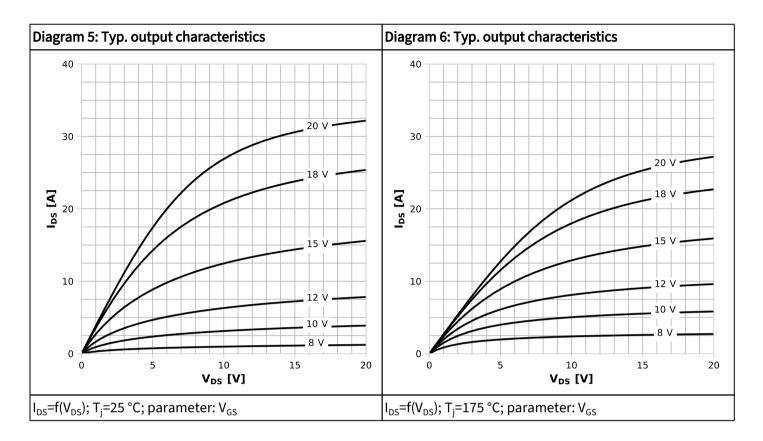


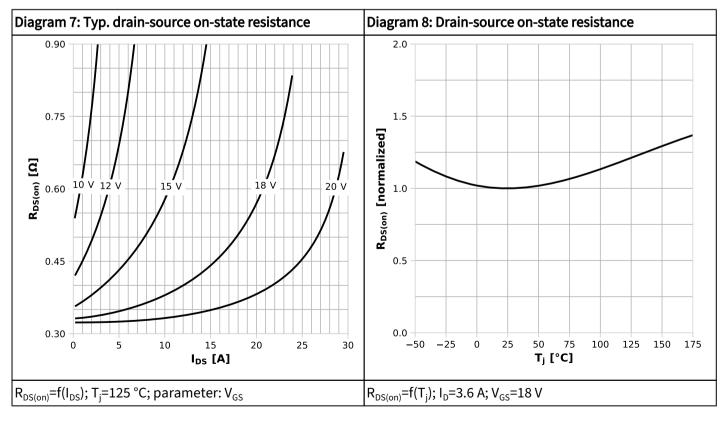
5 Electrical characteristics diagrams



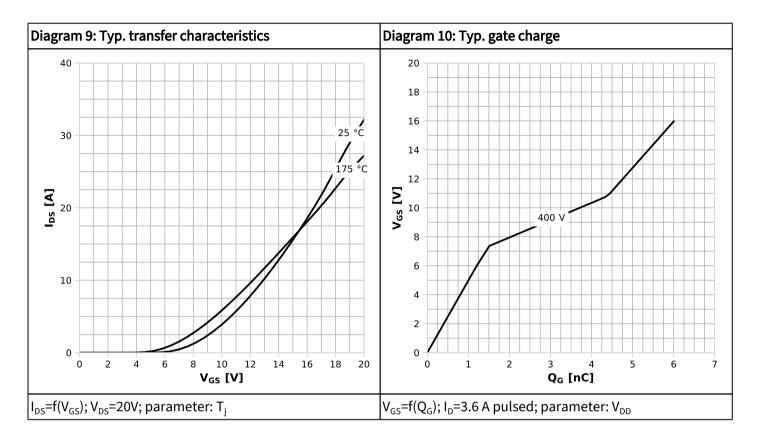


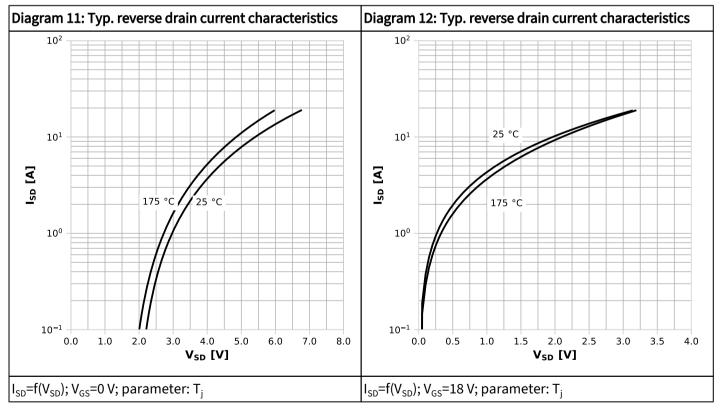




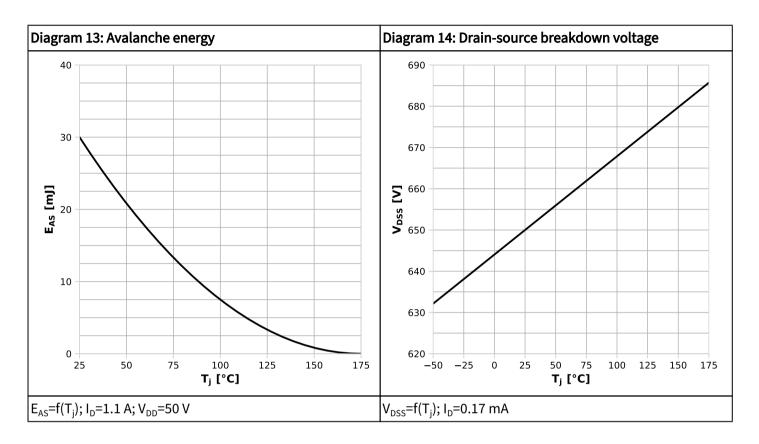


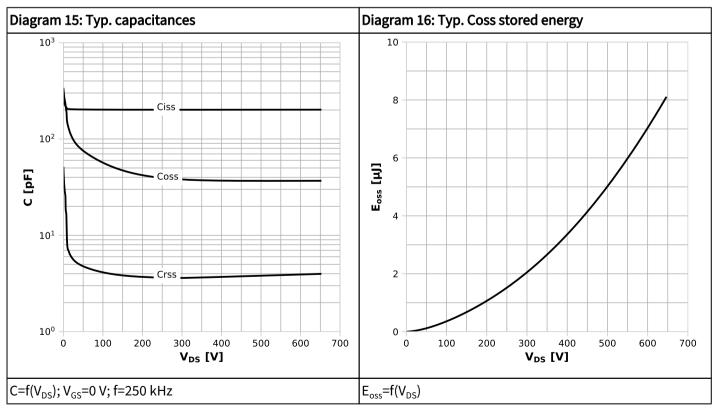




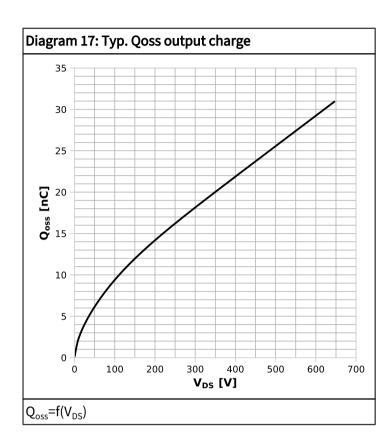














6 Test Circuits

Table 9 Body diode characteristics (CoolSiC)

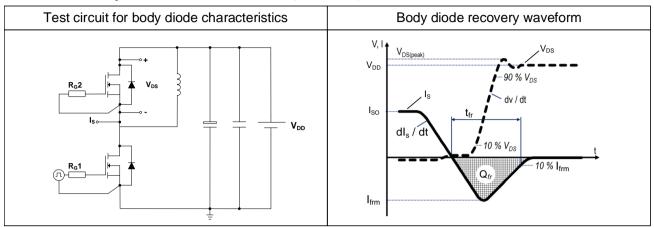


Table 10 Switching times (CoolSiC)

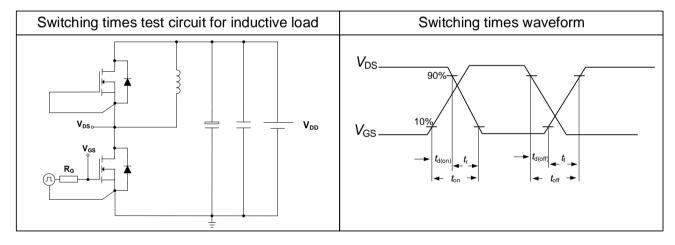


Table 11 Unclamped inductive load





7 Package Outlines

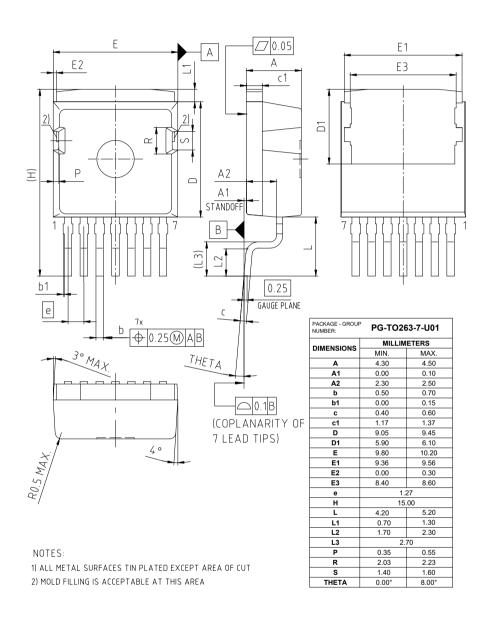


Figure 1 Outline PG-TO263-7, dimensions in mm



8 Appendix A

Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Webpage
- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Application Note
- IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Simulation Model
- IFX Design tools

CoolSiC™ MOSFET 650 V G1



Revision History

IMBG65R260M1H

Revision 2024-08-26, Rev. 2.1

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2021-12-10	Release of final version
2.1	2024-08-26	IDSS update, nomenclature update, datasheet layout update

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